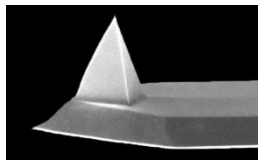
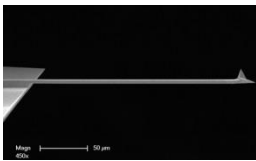
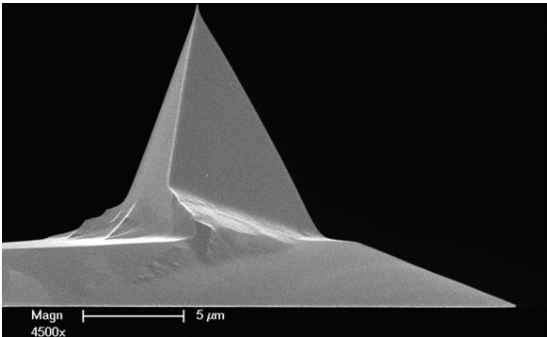




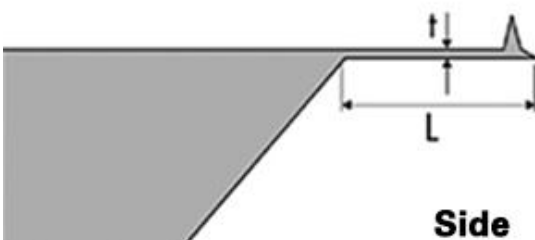
## FMV-PT

Conductive Coating AFM Probes



### Models

10-Pack  
Reflex  
Coating



For more information email:  
[afmprobeorders@bruker.com](mailto:afmprobeorders@bruker.com) or visit:

ValueAFMProbes.com

## Product Description

Value Line etched Silicon probes with conductive Platinum-Iridium (PtIr) coating on the tip for electrical characterization of samples.

**Specifications:** 2.8 N/m, 75 kHz, 25 nm tip radius, PtIr reflex coating. Conductive PtIr coated tip that is ideal for various contact mode electrical applications such as:

- Tunneling AFM and Conductive AFM
- Scanning Capacitance Microscopy (SCM)
- Piezoforce Microscopy (PFM)
- Electrical Force Microscopy (EFM)
- Surface Potential or Kelvin Probe Force Microscopy

## Tip Specification

Geometry:	Standard (Steep)
Tip Height (h):	10 - 15μm
Front Angle (FA):	25 ± 2.5°
Back Angle (BA):	15 ± 2.5°
Side Angle (SA):	22.5 ± 2.5°
Tip Radius (Nom):	25 nm
Tip SetBack (TSB)(Nom):	15 μm
Tip Set Back (TSB)(RNG):	5-25 μm
Tip Coating:	Conductive PtIr

## Cantilever Specification

Material:	0.01 - 0.025 Ωcm Antimony (n) doped Si
Geometry:	Rectangular
Cantilevers Number:	1
Cantilever Thickness (Nom):	2.75 μm
Cantilever Thickness (RNG):	2.0 - 3.5 μm
Front Side Coating:	Conductive PtIr
Back Side Coating:	Reflective PtIr